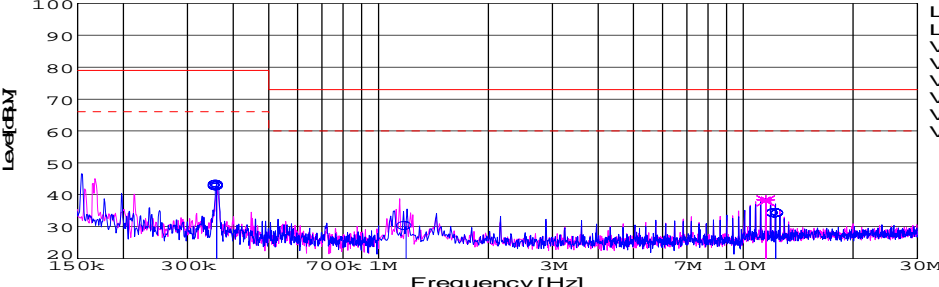
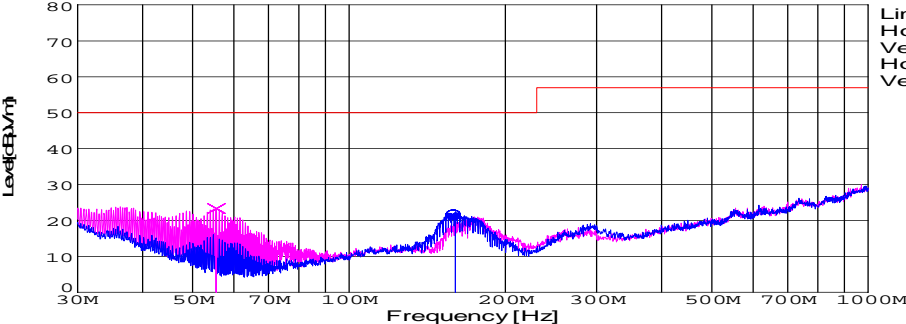


DATA SHEET							Date	18-Feb-09		
Model	SUTS60505						Temp.	25 degreeC		
Test	EMI Line conduction & Radiated emission						Humid.	45 %RH		
							Tested by	D.Joboji		
LINE CONDUCTION										
Model Name : SUTS60505			Temp. : 25							
Model No. :			Humi. : 45							
Serial No. :			Date : 2009/2/18 15:57							
Points : 4			Test Equip. : R3132,ESPC							
Detector : PEAK/QP/Ave.			Comment :							
Line Mode : VA/VB										
Power Supply : DC 5V										
Limit1: [EN 55022] Class A(QP)										
Limit2: [EN 55022] Class A(Ave.)										
							Limit1(QP) Limit2(Ave.) VA(PEAK) VB(PEAK) VA(QP) VA(Ave.) VB(QP) VB(Ave.)			
							DC 5V			
Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.3603	33.1	32.7	9.8	42.9	42.5	VA	66	79	23.1	36.5
12.2391	24	23.9	10.1	34.1	34	VA	60	73	25.9	39
11.5211	28.4	28	10.1	38.5	38.1	VB	60	73	21.5	34.9

RADIATED EMISSION										
Model Name : SUTS60505			Power Supply : DC 5V							
Model No. :			Temp. : 25							
Serial No. :			Humi. : 45							
Points : 2			Date : 2009/2/10 19:19							
Detector : PEAK/QP			Test Equip. : R3132,ESPC							
Polarization : Hori. & Vert.			Comment :							
Limit: [EN 55022] Class A<3m>										
							Limit(QP) Horizontal(PEAK) Vertical(PEAK) Horizontal(QP) Vertical(QP)			
							DC 5V			
Frequency [MHz]	MeterReading (QP) [dBuV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level(QP) [dBuV/m]	Angle [°]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
160.375	43	BL	9.9	-31.5	21.4	202	150	Hori.	50	28.6
55.522	49.8	BL	5.6	-32.1	23.3	114	109	Vert.	50	26.7

## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission



# COSEL

## Conditions

Test : EMI  
Model Name : SUTS/SUTW 605□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

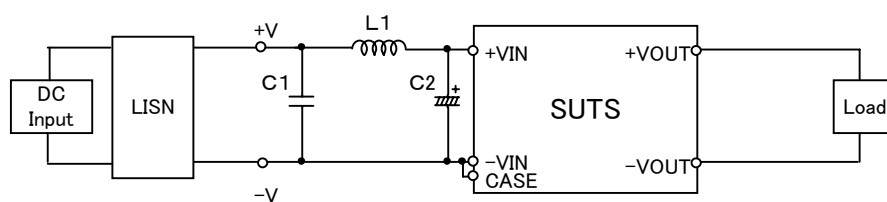


Fig.1 Testing circuitry 1

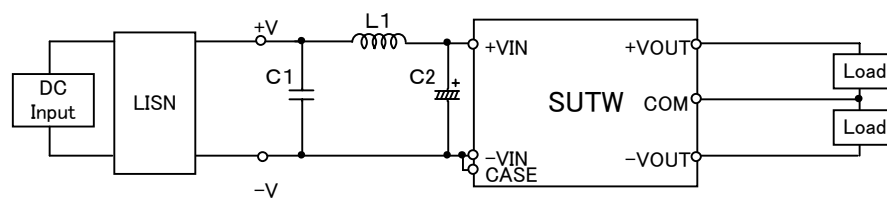


Fig.2 Testing circuitry 2

L1 :	0.5 $\mu$ H	CY3H-R50	(KORIN ELECTRONICS)
C1 :	25V    2.2 $\mu$ F	C3216JB1E225M	(TDK)
C2 :	16V    470 $\mu$ F	LXZ16VB470(M)	(NIPPON CHEMI-COM)